

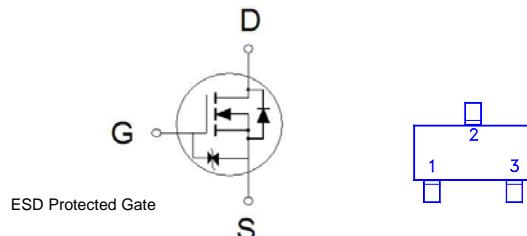
NIKO-SEM
**N-Channel Logic Level Enhancement
Mode Field Effect Transistor**
PZ2N7002Y

SOT-323

Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
60V	2Ω	290mA

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNITS
Drain-Source Voltage		V_{DS}	60		V
Gate-Source Voltage		V_{GS}	± 20		V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	290		mA
	$T_A = 70^\circ\text{C}$		230		
Pulsed Drain Current ¹		I_{DM}	1		A
Power Dissipation	$T_A = 25^\circ\text{C}$	P_D	0.34		W
	$T_A = 70^\circ\text{C}$		0.21		
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-40 to 150		° C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		368	° C / W

¹Pulse width limited by maximum junction temperature.
ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 100\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 100\mu\text{A}$	1.0	1.8	2.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 16\text{V}$			± 30	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 10\text{V}, V_{GS} = 10\text{V}$	1			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 3.5\text{V}, I_D = 10\text{mA}$		2.1	5	Ω
		$V_{GS} = 4.5\text{V}, I_D = 100\text{mA}$		1.7	3	
		$V_{GS} = 10\text{V}, I_D = 200\text{mA}$		1.6	2	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 20\text{V}, I_D = 200\text{mA}$		0.5		S

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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		36		pF
Output Capacitance	C_{oss}			10		
Reverse Transfer Capacitance	C_{rss}			6		
Total Gate Charge ²	Q_g	$V_{DS} = 30V, V_{GS} = 10V,$ $I_D = 1A$		1.6		nC
Gate-Source Charge ²	Q_{gs}			0.2		
Gate-Drain Charge ²	Q_{gd}			1		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S	$I_F = 200mA, V_{GS} = 0V$			280	mA
Forward Voltage ¹	V_{SD}				1.2	V

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.**REMARK: ESD Protected Gate, 2KV HBM**

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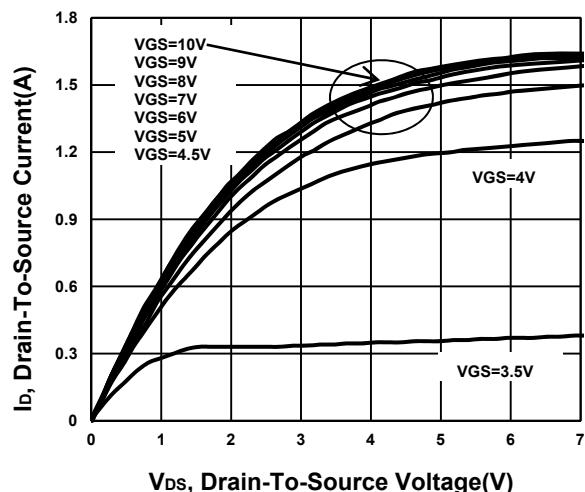
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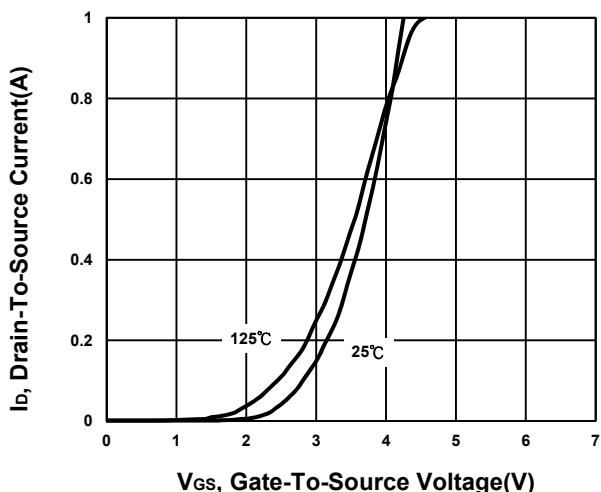
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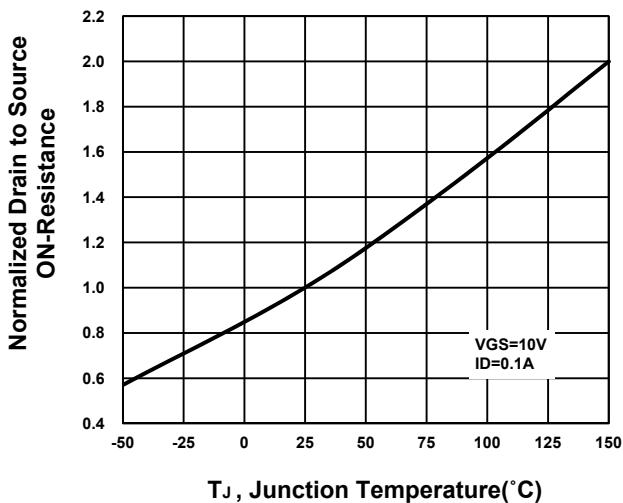
Output Characteristics



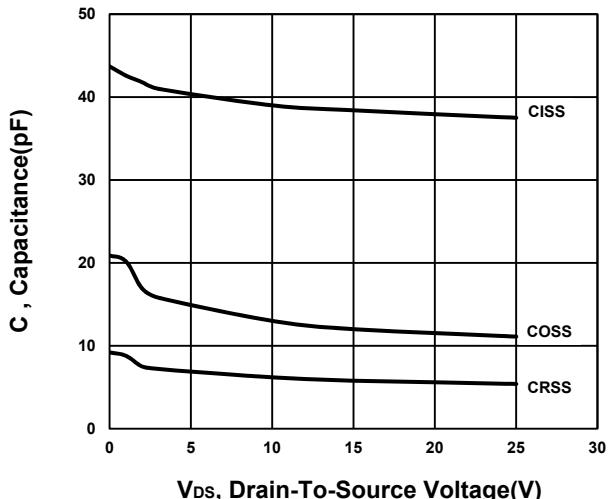
Transfer Characteristics



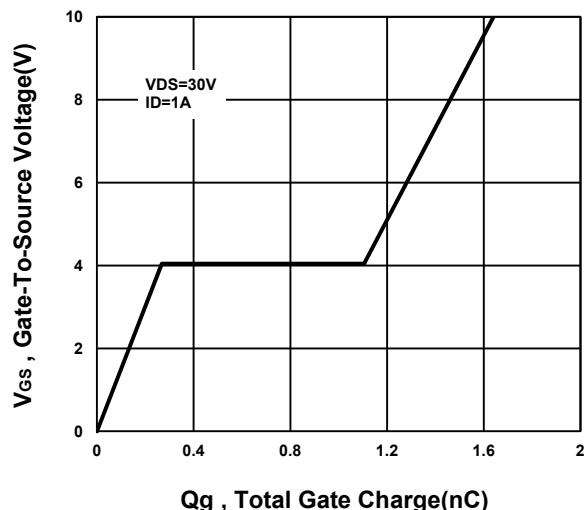
On-Resistance VS Temperature



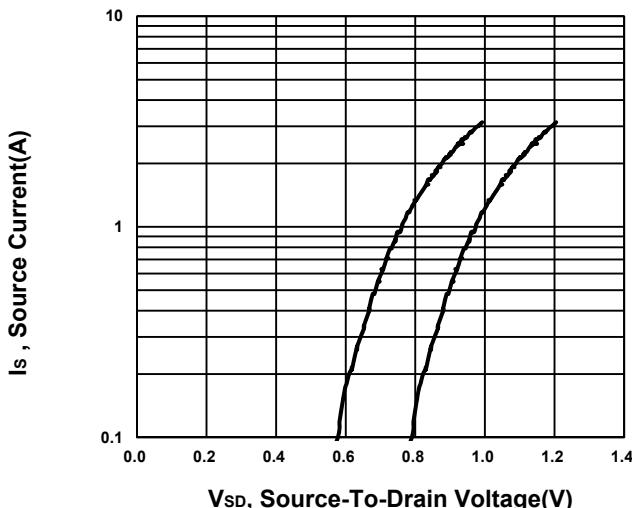
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage



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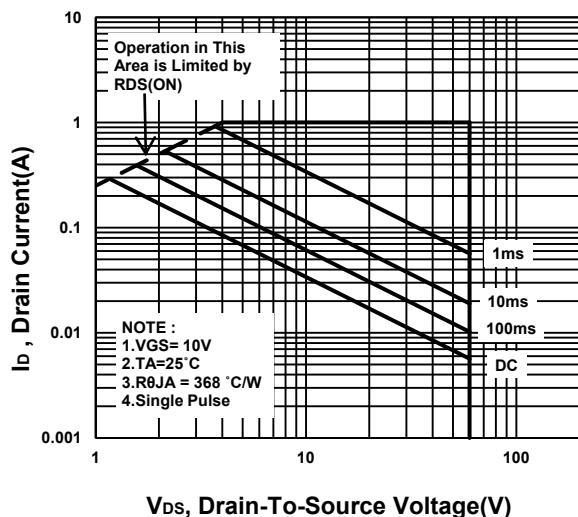
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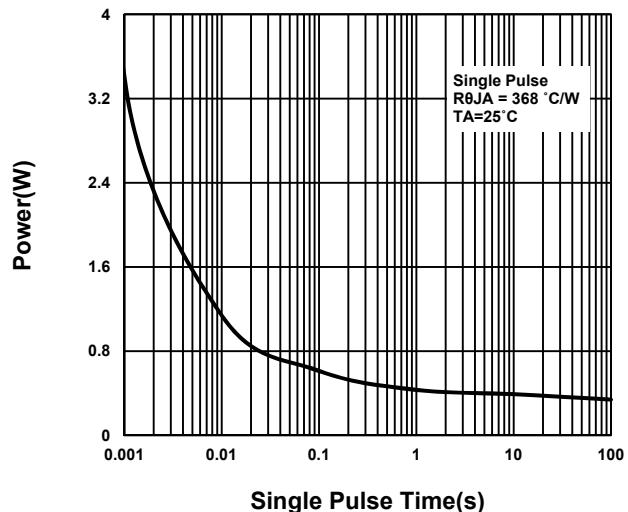
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Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

